CMOS SUPERSYNC FIFO™ 16.384 x 9. 32.768 x 9

IDT72261 **IDT72271**

FEATURES:

- 16.384 x 9-bit storage capacity (IDT72261)
- 32,768 x 9-bit storage capacity (IDT72271)
- 10ns read/write cycle time (8ns access time)
- Retransmit Capability
- Auto power down reduces power consumption
- Master Reset clears entire FIFO. Partial Reset clears data, but retains programmable settings
- Empty, Full and Half-Full flags signal FIFO status
- Programmable Almost-Empty and Almost-Full flags, each (

- · Easily expandable in depth and width
- Independent Read and Write Clocks (permit simula) neous reading and writing with one clock signal
- Available in the 64-pin Thin Quad Flat Pack (TQFP) and the 64-pin Slim Thin Quad Flat Pack (STQFP)
- Output enable puts data outputs into high impedance
- High-performance submicron CMOS technology
- Industrial temperature range (–40°C to +85°C) is available

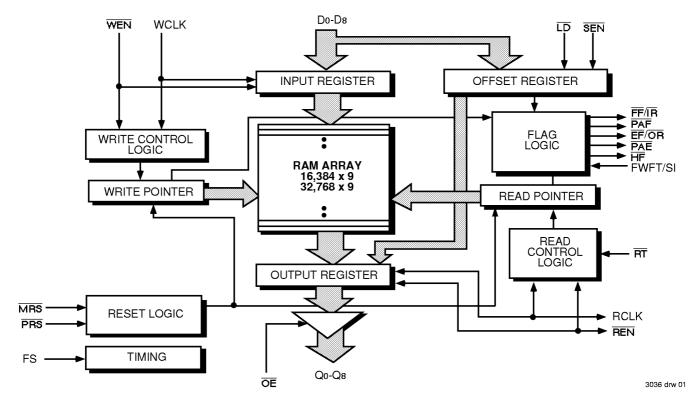
DESCRIPTION:

The IDT72261/72271 are monolithic, CMOS, high capacity, high speed, low power first-in, first-out (FIFO) memories with clocked read and write controls. These FIFOs are applicable for a wide variety of data buffering needs, such as optical disk controllers, local area networks (LANs), and interprocessor communication.

Both FIFOs have a 9-bit input port (Dn) and a 9-bit output port (Qa) The input port is controlled by a free-running clock (WCLK) and a data input enable pin (WEN). Data is written into the • Select IDT Standard timing (using EF and Tags) or pip (REN). The Read Clock can be fied to the Main Comparable of the World Fall Through timing (using OF and IDT). for dual clock operation. An Output Enable pin (\overline{OE}) is provided on the read port for three-state control of the outputs.

> These devices have two modes of operation: In the IDT Standard mode, the first word written to the FIFO is deposited into the memory array. A read operation is required to access that word. In the First Word Fall Through mode (FWFT), the first word written to an empty FIFO appears automatically on the outputs, no read operation required. The state of the FWFT/SI pin during Master Reset determines the mode in use.

FUNCTIONAL BLOCK DIAGRAM



SuperSyncFIFO is a trademark and the IDT logo is a registered trademark of Integrated Device Technology, Inc.

These FIFOs have five flag functions, EF/OR (Empty Flag or Output Ready), FF/IR (Full Flag or Input Ready), and HF (Half-Full flag). The EF and FF functions are selected in the IDT Standard mode.

The IR and OR functions are selected in the First Word Fall Through mode. IR indicates that the FIFO has free space to receive data. OR indicates that data contained in the FIFO is available for reading.

HF is a flag whose threshold is fixed at the halfway point in memory. This flag can always be used irrespective of mode.

PAE, PAF can be programmed independently to any point in memory. They also can be used irrespective of mode. Programmable offsets determine the flag threshold and can be loaded by two methods: parallel or serial. Two default offset settings are also provided, such that PAE can be set at 127 or 1.023 locations from the empty boundary and the PAF threshold can be set at 127 or 1,023 locations from the full boundary. All these choices are made with \overline{LD} during Master Reset.

In the serial method, \overline{SEN} together with \overline{LD} are used to load the offset registers via the Serial Input (SI). In the parallel method, WEN together with LD can be used to load the offset registers via D_n . \overline{REN} together with \overline{LD} can be used to read the offsets in parallel from Qn regardless of whether serial or parallel offset loading is selected.

During Master Reset (MRS), the read and write pointers are set to the first location of the FIFO. The FWFT line selects IDT Standard mode or FWFT mode. The \overline{LD} pin selects one of two partial flag default settings (127 or 1,023) and, also, serial or parallel programming. The flags are updated accordingly.

The Partial Reset (PRS) also sets the read and write pointers to the first location of the memory. However, the mode setting, programming method, and partial flag offsets are not altered. The flags are updated accordingly. PRS is useful for resetting a device in mid-operation, when reprogramming offset registers may not be convenient.

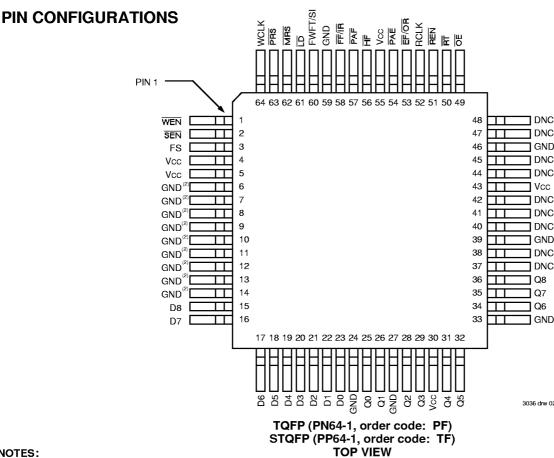
The Retransmit function allows the read pointer to be reset to the first location in the RAM array. It is synchronized to RCLK when RT is LOW. This feature is convenient for sending the same data more than once.

If, at any time, the FIFO is not actively performing a function, the chip will automatically power down. This occurs if neither a read nor a write occurs within 10 cycles of the faster clock, RCLK or WCLK. During the Power down state, supply current consumption (Icc2) is at a minimum. Initiating any operation (by activating control inputs) will immediately take the device out of the Power down state.

These devices are depth expandable. The addition of external components is unnecessary. The IR and OR functions, together with REN and WEN, are used to extend the total FIFO memory capacity.

The FS line ensures optimal data flow through the FIFO. It is tied to GND if the RCLK frequency is higher than the WCLK frequency or to Vcc if the RCLK frequency is lower than the WCLK frequency.

The IDT72261/72271 is fabricated using IDT's high speed submicron CMOS technology.



- DNC = Do not connect.
- This pin may either be tied to ground or left open.

PIN DESCRIPTION

Symbol	Name	I/O	Description
Do-D8	Data Inputs	Ι	Data inputs for a 9-bit bus.
MRS	Master Reset	_	MRS initializes the read and write pointers to zero and sets the output register to all zeroes. During Master Reset, the FIFO is configured for either FWFT or IDT Standard mode, one of two programmable flag default settings, and serial or parallel programming of the offset settings.
PRS	Partial Reset	Ι	PRS initializes the read and write pointers to zero and sets the output register to all zeroes. During Partial Reset, the existing mode (IDT or FWFT), programming method (serial or parallel), and programmable flag settings are all retained.
RT	Retransmit	Ι	Allows data to be resent starting with the first location of FIFO memory.
FWFT/SI	First Word Fall Through/Serial In	I	During Master Reset, selects First Word Fall Through or IDT Standard mode. After Master Reset, this pin functions as a serial input for loading offset registers
WCLK	Write Clock	I	When enabled by $\overline{\text{WEN}}$, the rising edge of WCLK writes data into the FIFO and offsets into the programmable registers.
WEN	Write Enable	I	WEN enables WCLK for writing data into the FIFO memory and offset registers.
RCLK	Read Clock	_	When enabled by $\overline{\text{REN}}$, the rising edge of RCLK reads data from the FIFO memory and offsets from the programmable registers.
REN	Read Enable	_	REN enables RCLK for reading data from the FIFO memory and offset registers.
ŌĒ	Output Enable		$\overline{\sf OE}$ controls the output impedance of ${\sf Qn}$
SEN	Serial Enable	-	SEN enables serial loading of programmable flag offsets
LD	Load	_	During Master Reset, $\overline{\text{LD}}$ selects one of two partial flag default offsets (127 and 1,023) and determines programming method, serial or parallel. After Master Reset, this pin enables writing to and reading from the offset registers.
FS	Frequency Select	Ι	The FS setting optimizes data flow through the FIFO.
FF/IR	Full Flag/ Input Ready	0	In the IDT Standard mode, the FF function is selected. FF indicates whether or not the FIFO memory is full. In the FWFT mode, the IR function is selected. IR indicates whether or not there is space available for writing to the FIFO memory.
EF/OR	Empty Flag/ Output Ready	0	In the IDT Standard mode, the $\overline{\text{EF}}$ function is selected. $\overline{\text{EF}}$ indicates whether or not the FIFO memory is empty. In FWFT mode, the $\overline{\text{OR}}$ function is selected. $\overline{\text{OR}}$ indicates whether or not there is valid data available at the outputs.
PAF	Programmable Almost-Full Flag	0	PAF goes HIGH if the number of free locations in the FIFO memory is more than offset m which is store in almost-full which is stored in the Full Offset register. PAF goes LOW if the number of free locations in the FIFO memory is less than m.
PAE	Programmable Almost-Empty Flag	0	PAE goes LOW if the number of words in the FIFO memory is less than offset n which is stored in the Empty Offset register. PAE goes HIGH if the number of words in the FIFO memory is greater than offset n.
HF	Half-Full Flag	0	HF indicates whether the FIFO memory is more or less than half-full.
Q0–Q8	Data Outputs	0	Data outputs for a 9-bit bus.
Vcc	Power		+5 volt power supply pins.
GND	Ground		Ground pins.

ABSOLUTE MAXIMUM RATINGS

Symbol	Rating	Com'l & Ind'l	Unit
VTERM	Terminal Voltage with respect to GND	-0.5 to +7.0	٧
Tstg	Storage Temperature	-55 to +125	°C
lout	DC Output Current	-50 to +50	mA

NOTE: 3036 tbl 0

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RAT-INGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS

Symbol	Parameter	Min.	Тур.	Max.	Unit
Vcc	Supply Voltage Commercial/Industrial	4.5	5.0	5.5	٧
GND	Supply Voltage	0	0	0	>
ViH	Input High Voltage Commercial/Industrial	2.0		1	>
VIL ⁽¹⁾	Input Low Voltage Commercial/Industrial	_	_	0.8	V
Та	Operating Temperature Commercial	0		70	°C
TA	Operating Temperature Industrial	-40	_	85	°C

NOTE: 3036 tbl 03

1. 1.5V undershoots are allowed for 10ns once per cycle.

DC ELECTRICAL CHARACTERISTICS

(Commercial: $Vcc = 5V \pm 10\%$, $TA = 0^{\circ}C$ to $+70^{\circ}C$; Industrial: $Vcc = 5V \pm 10\%$, $TA = -40^{\circ}C$ to $+85^{\circ}C$)

			DT72261L IDT72271L nmercial & Industr i⊥K = 10, 12, 15, 20		
Symbol	Parameter	Min.	Тур.	Max.	Unit
I LI ⁽²⁾	Input Leakage Current (any input)	– 1	_	1	μΑ
ILO ⁽³⁾	Output Leakage Current	-10	_	10	μА
Voн	Output Logic "1" Voltage, IOH = -2 mA	2.4	_	_	V
Vol	Output Logic "0" Voltage, IOL = 8 mA	_	_	0.4	V
ICC1 ^(4,5,6)	Active Power Supply Current	_	_	150 ⁽⁹⁾	mA
ICC2 ^(4,7,8)	Standby Current	_	_	15 ⁽⁹⁾	mA

NOTES:

3036 tbl 04

- 1. Industrial temperature range product for the 20ns speed grade is available as a standard device. All other speed grades are available by special order.
- 2. Measurements with $0.4 \le V_{IN} \le V_{CC}$.
- 3. $\overline{OE} \ge V_{IH}, 0.4 \le V_{OUT} \le V_{CC}$.
- 4. Tested with outputs open (IOUT = 0).
- 5. RCLK and WCLK toggle at 20 MHz and data inputs switch at 10 MHz.
- 6. Typical Icc1 = 85 + 1.47*fs + 0.02*CL*fs with Vcc = 3.3V, TA = 25°C, fs = WCLK frequency = RCLK frequency (in MHz, using TTL levels), data switching at fs/2, CL = capacitive load (in pF).
- 7. No data written or read for more than 10 cycles.
- 8. All Inputs = Vcc 0.2V or GND + 0.2V, except RCLK and WCLK, which toggle at 20 MHz.
- 9. For product with date code Y9XXX, the parameters are Icc1 = 75mA and Icc2 = 20mA. For more information, contact your local IDT sales office.

CAPACITANCE (TA = +25°C, f = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Max.	Unit
CIN ⁽²⁾	Input Capacitance	VIN = 0V	10	pF
COUT ^(1,2)	Output Capacitance	VOUT = 0V	10	pF

NOTES:

1. With output deselected, $(\overline{OE} \ge V \Vdash)$.

2. Characterized values, not currently tested.

AC ELECTRICAL CHARACTERISTICS(1)

(Commercial: $Vcc = 5V \pm 10\%$, TA = 0°C to +70°C; Industrial: $Vcc = 5V \pm 10\%$, TA = -40°C to +85°C)

					nercial			Com'l 8	k Ind'l ⁽¹⁾	
		7226			1L12		1L15		1L20	
		7227			1L12	72271L15		72271L20		l l
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
fs tA	Clock Cycle Frequency Data Access Time	2	100 8	2	83.3 9	2	66.7 10	2	50 12	MHz
					-					ns
tCLK	Clock Cycle Time	10	_	12		15	_	20	_	ns
tclkh	Clock High Time	4.5	_	5		6	_	8	_	ns
tclkl	Clock Low Time	4.5(3)		5(3)		6 ⁽³⁾		8	_	ns
tDS	Data Setup Time	3.5		3.5		4		5		ns
tDH	Data Hold Time	0	_	0		1	_	1	_	ns
tens	Enable Setup Time	3.5	_	3.5		4	_	5	_	ns
tenh	Enable Hold Time	0	_	0	_	1		1	_	ns
tlds	Load Setup Time	3.5	_	3.5	_	4	_	5	_	ns
tldh	Load Hold Time	6.5		8.5	_	10	_	10	_	ns
trs	Reset Pulse Width ⁽⁴⁾	10	_	12		15	_	20	_	ns
trss	Reset Setup Time	10		12	_	15	_	20	_	ns
trsr	Reset Recovery Time	10	_	12	_	15	_	20	_	ns
trsf	Reset to Flag and Output Time	_	10	_	12	_	15	_	20	ns
tFWFT	Mode Select Time	0	_	0	_	0	_	0	_	ns
trts	Retransmit setup Time	3.5	_	3.5	_	4	_	5	_	ns
tolz	Output Enable to Output in Low Z ⁽⁵⁾	0	_	0	_	0	_	0	_	ns
toE	Output Enable to Output Valid	3	7	3	7.5	3	8	3	10	ns
tohz	Output Enable to Output in High Z ⁽⁵⁾	3	7	3	7.5	3	8	3	10	ns
twff	Write Clock to FF or IR	_	8	_	9	_	10	_	12	ns
tref	Read Clock to EF or OR	_	8	_	9	_	10	_	12	ns
tpaf	Write Clock to PAF	_	8	_	9	_	10	_	12	ns
tPAE	Read Clock to PAE	_	8	_	9	_	10	_	12	ns
tHF	Clock to HF		16	_	18		20		22	ns
tskew1	Skew time between RCLK and WCLK for FF and IR	8	1	10		12	_	15	_	ns
tskew2	Skew time between RCLK and WCLK for PAE and PAF	15		18	_	21	_	25	_	ns

NOTES:

3036 tbl 06

- 1. Industrial temperature range is available by special order for speed grades faster than 20ns.
- 2. All AC timings apply to both Standard IDT mode and First Word Fall Through mode.
- For the RCLK line: tclkl (min.) = 7 ns only when reading the offsets from the programmable flag
 registers; otherwise, use the table value. For the WCLK line, use the tclkl (min.) value given
 in the table.
- 4. Pulse widths less than minimum values are not allowed.
- 5. Values guaranteed by design, not currently tested.

AC TEST CONDITIONS

Input Pulse Levels Input Rise/Fall Times	GND to 3.0V 3ns 1.5V
Input Timing Reference Levels Output Reference Levels Output Load	1.5V 1.5V See Figure 1

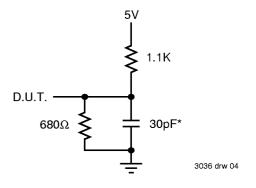


Figure 1. Output Load

* Includes jig and scope capacitances.

SIGNAL DESCRIPTIONS:

INPUTS:

DATA IN (Do - D8)

Data inputs for 9-bit wide data.

CONTROLS:

MASTER RESET (MRS)

A Master Reset is accomplished whenever the Master Reset (MRS) input is taken to a LOW state. This operation sets the internal read and write pointers to the first location of the RAM array. PAE will go LOW, PAF will go HIGH, and HF will go HIGH.

If FWFT is LOW during Master Reset then the IDT Standard mode, along with $\overline{\text{EF}}$ and $\overline{\text{FF}}$ are selected. $\overline{\text{EF}}$ will go LOW and $\overline{\text{FF}}$ will go HIGH. If FWFT is HIGH, then the First Word Fall Through mode (FWFT), along with $\overline{\text{IR}}$ and $\overline{\text{OR}}$, are selected. $\overline{\text{OR}}$ will go HIGH and $\overline{\text{IR}}$ will go LOW.

If $\overline{\text{LD}}$ is LOW during Master Reset, then $\overline{\text{PAE}}$ is assigned a threshold 127 words from the empty boundary and $\overline{\text{PAF}}$ is assigned a threshold 127 words from the full boundary; 127 words corresponds to an offset value of 07FH. Following Master Reset, parallel loading of the offsets is permitted, but not serial loading.

If $\overline{\text{LD}}$ is HIGH during Master Reset, then $\overline{\text{PAE}}$ is assigned a threshold 1,023 words from the empty boundary and $\overline{\text{PAF}}$ is assigned a threshold 1,023 words from the full boundary; 1,023 words corresponds to an offset value of 3FFH. Following Master Reset, serial loading of the offsets is permitted, but not parallel loading.

Regardless of whether serial or parallel offset loading has been selected, parallel reading of the registers is always permitted. (See section describing the $\overline{\text{LD}}$ line for further details).

During a Master Reset, the output register is initialized to all zeroes. A Master Reset is required after power up, before a write operation can take place. MRS is asynchronous.

PARTIAL RESET (PRS)

A Partial Reset is accomplished whenever the Partial Reset (PRS) input is taken to a LOW state. As in the case of the Master Reset, the internal read and write pointers are set to the first location of the RAM array, PAE goes LOW, PAF goes HIGH, and HF goes HIGH.

Whichever mode is active at the time of partial reset, IDT Standard mode or First Word Fall Through, that mode will remain selected. If the IDT Standard mode is active, then $\overline{\text{FF}}$ will go HIGH and $\overline{\text{EF}}$ will go LOW. If the First Word Fall Through mode is active, then $\overline{\text{OR}}$ will go HIGH, and $\overline{\text{IR}}$ will go LOW

Following Partial Reset, all values held in the offset registers remain unchanged. The programming method (parallel or serial) currently active at the time of Partial Reset is also retained. The output register is initialized to all zeroes. PRS is asynchronous.

A Partial Reset is useful for resetting the device during the course of operation, when reprogramming flag settings may not be convenient.

RETRANSMIT (RT)

The Retransmit operation allows data that has already been read to be accessed again. There are two stages: first, a setup procedure that resets the read pointer to the first location of memory, then the actual retransmit, which consists of reading out the memory contents, starting at the beginning of memory.

Retransmit Setup is initiated by holding \overline{RT} LOW during a rising RCLK edge. \overline{REN} and \overline{WEN} must be HIGH before bringing \overline{RT} LOW. At least one word, but no more than Full - 2 words should have been written into the FIFO between Reset (Master or Partial) and the time of Retransmit Setup (Full = 16,384 words for the IDT72261, 32,768 words for the IDT72271).

If IDT Standard mode is selected, the FIFO will mark the beginning of the Retransmit Setup by setting \overline{EF} LOW. The change in level will only be noticeable if \overline{EF} was HIGH before setup. During this period, the internal read pointer is initialized to the first location of the RAM array.

When EF goes HIGH, Retransmit Setup is complete and read operations may begin starting with the first location in memory. Since IDT Standard mode is selected, every word read including the first word following Retransmit Setup requires a LOW on REN to enable the rising edge of RCLK. Writing operations can begin after one of two conditions have been met: EF is HIGH or 14 cycles of the faster clock (RCLK or WCLK) have elapsed since the RCLK rising edge enabled by the RT pulse.

The deassertion time of $\overline{\text{EF}}$ during Retransmit Setup is variable. The parameter tRTF1, which is measured from the rising RCLK edge enabled by $\overline{\text{RT}}$ to the rising edge of $\overline{\text{EF}}$ is described by the following equation:

where Tf is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the RCLK period.

Regarding $\overline{\text{FF}}$: Note that since no more than Full - 2 writes are allowed between a Reset and a Retransmit Setup, $\overline{\text{FF}}$ will remain HIGH throughout the setup procedure.

For IDT Standard mode, updating the PAE, HF, and PAF flags begins with the "first" REN-enabled rising RCLK edge following the end of Retransmit Setup (the point at which EF goes HIGH). This same RCLK rising edge is used to access the "first" memory location. HF is updated on the first RCLK rising edge. PAE is updated after two more rising RCLK edges. PAF is updated after the "first" rising RCLK edge, followed by the next two rising WCLK edges. (If the tskew2 specification is not met, add one more WCLK cycle.)

If FWFT mode is selected, the FIFO will mark the beginning of the Retransmit Setup by setting \overline{OR} HIGH. The change in level will only be noticeable if \overline{OR} was LOW before setup. During this period, the internal read pointer is set to the first location of the RAM array.

When $\overline{\text{OR}}$ goes LOW, Retransmit Setup is complete; at the same time, the contents of the first location are automatically displayed on the outputs. Since FWFT mode is selected, the first word appears on the outputs, no read request necessary. Reading all subsequent words requires a LOW on $\overline{\text{REN}}$ to enable the rising edge of RCLK. Writing operations can begin

after one of two conditions have been met: \overline{OR} is LOW or 14 cycles of the faster clock (RCLK or WCLK) have elapsed since the RCLK rising edge enabled by the \overline{RT} pulse.

The assertion time of \overline{OR} during Retransmit Setup is variable. The parameter tRTF2, which is measured from the rising RCLK edge enabled by \overline{RT} to the falling edge of \overline{OR} is described by the following equation:

$$trter = 14 T_f + 4 Trclk (in ns)$$

where Tf is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the RCLK period. Note that a Retransmit Setup in FWFT mode requires one more RCLK cycle than in IDT Standard mode.

Regarding \overline{IR} : Note that since no more than Full - 2 writes are allowed between a Reset and a Retransmit Setup, \overline{IR} will remain LOW throughout the setup procedure.

For FWFT mode, updating the PAE, HF, and PAF flags begins with the "last" rising edge of RCLK before the end of Retransmit Setup. This is the same edge that asserts OR and automatically accesses the first memory location. Note that, in this case, REN is not required to initiate flag updating. HF is updated on the "last" RCLK rising edge. PAE is updated after two more rising RCLK edges. PAF is updated after the "last" rising RCLK edge, followed by the next two rising WCLK edges. (If the tskew2 specification is not met, add one more WCLK cycle.)

RT is synchronized to RCLK. The Retransmit operation is useful in the event of a transmission error on a network, since it allows a data packet to be resent.

FIRST WORD FALL THROUGH/SERIAL IN (FWFT/SI)

This is a dual purpose pin. During Master Reset, the state of the FWFT/SI helps determine whether the device will operate in IDT Standard mode or First Word Fall Through (FWFT) mode.

If, at the time of Master Reset, FWFT/SI is LOW, then IDT Standard mode will be selected. This mode uses the Empty Flag ($\overline{\text{EF}}$) to indicate whether or not there are any words present in the FIFO memory. It also uses the Full Flag function ($\overline{\text{FF}}$) to indicate whether or not the FIFO memory has any free space for writing. In IDT Standard mode, every word read from the FIFO, including the first, must be requested using the Read Enable ($\overline{\text{REN}}$) line.

If, at the time of Master Reset, FWFT/SI is HIGH, then FWFT mode will be selected. This mode uses Output Ready (\overline{OR}) to indicate whether or not there is valid data at the data outputs (Qn). It also uses Input Ready (\overline{IR}) to indicate whether or not the FIFO memory has any free space for writing. In the FWFT mode, the first word written to an empty FIFO goes directly to Qn, no read request necessary. Subsequent words must be accessed using the Read Enable (\overline{REN}) line.

After Master Reset, FWFT/SI acts as a serial input for loading PAE and PAF offsets into the programmable registers. The serial input function can only be used when the serial loading method has been selected during Master Reset. FWFT/SI functions the same way in both IDT Standard and FWFT modes.

WRITE CLOCK (WCLK)

A write cycle is initiated on the rising edge of the Write Clock (WCLK). Data setup and hold times must be met with respect to the LOW-to-HIGH transition of the WCLK. The Write and Read Clocks lines can either be asynchronous or coincident.

WRITE ENABLE (WEN)

When Write Enable ($\overline{\text{WEN}}$) is LOW, data can be loaded into the input register on the rising edge of every WCLK cycle. Data is stored in the RAM array sequentially and independently of any on-going read operation.

When WEN is HIGH, the input register holds the previous data and no new data is loaded into the FIFO.

To prevent data overflow in the IDT Standard mode, $\overline{\text{FF}}$ will go LOW, inhibiting further write operations. Upon the completion of a valid read cycle, $\overline{\text{FF}}$ will go HIGH allowing a write to occur. $\overline{\text{WEN}}$ is ignored when the FIFO is full.

To prevent data overflow in the FWFT mode, \overline{IR} will go HIGH, inhibiting further write operations. Upon the completion of a valid read cycle, \overline{IR} will go LOW allowing a write to occur.

WEN is ignored when the FIFO is full.

READ CLOCK (RCLK)

Data can be read on the outputs, on the rising edge of the Read Clock (RCLK), when Output Enable (\overline{OE}) is set LOW. The Write and Read Clocks can be asynchronous or coincident.

READ ENABLE (REN)

When Read Enable ($\overline{\text{REN}}$) is LOW, data is loaded from the RAM array into the output register on the rising edge of the RCLK.

When REN is HIGH, the output register holds the previous data and no new data is loaded into the output register.

In the IDT Standard mode, every word accessed at Qn, including the first word written to an empty FIFO, must be requested using $\overline{\text{REN}}$. When all the data has been read from the FIFO, the Empty Flag ($\overline{\text{EF}}$) will go LOW, inhibiting further read operations. $\overline{\text{REN}}$ is ignored when the FIFO is empty. Once a write is performed, $\overline{\text{EF}}$ will go HIGH after tFWL1 + tREF and a read is permitted.

In the FWFT mode, the first word written to an empty FIFO automatically goes to the outputs $Q_{\text{n}},$ no need for any read request. In order to access all other words, a read must be executed using $\overline{\text{REN}}.$ When all the data has been read from the FIFO, Output Ready $(\overline{\text{OR}})$ will go HIGH, inhibiting further read operations. $\overline{\text{REN}}$ is ignored when the FIFO is empty. Once a write is performed, $\overline{\text{OR}}$ will go LOW after tFWL2+ tREF, when the first word appears at Q_{n} ; if a second word is written into the FIFO, then $\overline{\text{REN}}$ can be used to read it out.

SERIAL ENABLE (SEN)

Serial Enable is (\overline{SEN}) is an enable used only for serial programming of the offset registers. The serial programming method must be selected during Master Reset. \overline{SEN} is always used in conjunction with \overline{LD} . When these lines are both LOW, data at the SI input can be loaded into the input register one bit for each LOW-to-HIGH transition of WCLK.

When SEN is HIGH, the programmable registers retains the previous settings and no offsets are loaded.

SEN functions the same way in both IDT Standard and FWFT modes.

OUTPUT ENABLE (OE)

When Output Enable (\overline{OE}) is enabled (LOW), the parallel output buffers receive data from the output register. When \overline{OE} is HIGH, the output data bus (Qn) goes into a high impedance state.

LOAD (LD)

This is a dual purpose pin. During Master Reset, the state of the Load line (\overline{LD}) determines one of two default values (127 or 1,023) for the \overline{PAE} and \overline{PAF} flags, along with the method by which these flags can be programmed, parallel or serial. After Master Reset, \overline{LD} enables write operations to and read operations from the registers. Only the offset loading method currently selected can be used to write to the registers. Aside from Master Reset, there is no other way change the loading method. Registers can be read only in parallel; this can be accomplished regardless of whether serial or the parallel loading has been selected.

Associated with each of the programmable flags, \overline{PAE} and \overline{PAF} , are two registers which can either be written to or read from. Offset values contained in these registers determine how many words need to be in the FIFO memory to switch a partial flag. A LOW on \overline{LD} during Master Reset selects a default \overline{PAE} offset value of 07FH (a threshold 127 words from the empty boundary), a default \overline{PAF} offset value of 07FH (a threshold 127 words from the full boundary), and parallel loading of other offset values. A HIGH on \overline{LD} during Master Reset selects a default \overline{PAE} offset value of 3FFH (a threshold 1,023 words from the empty boundary), a default \overline{PAF} offset value of 3FFH (a threshold 1,023 words form the full boundary), and serial loading of other offset values.

The act of writing offsets (in parallel or serial) employs a dedicated write offset register pointer. The act of reading offsets employs a dedicated read offset register pointer. The two pointers operate independently; however, a read and a write should not be performed simultaneously to the offset registers. A Master Reset initializes both pointers to the Empty Offset (LSB) register. A Partial Reset has no effect on the position of these pointers.

Once serial offset loading has been selected, then programming \overline{PAE} and \overline{PAF} proceeds as follows: When \overline{LD} and

LD	WEN	REN	SEN	WCLK	RCLK	Selection
0	0	1	1		Х	Parallel write to registers: Empty Offset (LSB) Empty Offset (MSB) Full Offset (LSB) Full Offset (MSB)
0	1	0	1	Х	4	Parallel read from registers: Empty Offset (LSB) Empty Offset (MSB) Full Offset (MSB) Full Offset (MSB)
0	1	1	0		х	Serial shift into registers: 28 bits for the 72261 30 bits for the 72271 1 bit for each rising WCLK edge Starting with Empty Offset (LSB) Ending with Full Offset (MSB)
Х	1	1	1	Х	Х	No Operation
1	0	Х	Х		Х	Write Memory
1	Х	0	Х	Х		Read Memory
1	1	1	Х	Х	Х	No Operation

NOTES:

- 1. Only one of the two offset programming methods, serial or parallel, is available for use at any given time.
- 2. The programming method can only be selected at Master Reset.
- 3. Parallel reading of the offset registers is always permitted regardless of which programming method has been selected.
- The programming sequence applies to both IDT Standard and FWFT modes.

 $\overline{\text{SEN}}$ are set LOW, data on the SI input are written, one bit for each WCLK rising edge, starting with the Empty Offset LSB (8 bits for both the IDT72261 and IDT72271), then the Empty Offset MSB (6 bits for the IDT72261, 7 bits for the IDT72271), then the Full Offset LSB (8 bits for both the IDT72261 and IDT72271), ending with the Full Offset MSB (6 bits for the IDT72261, 7 bits for the IDT72271). A total of 28 bits are necessary to program the IDT72261; a total of 30 bits are necessary to program the IDT72261; a total of 30 bits are necessary to program the IDT72271. Individual registers cannot be loaded serially; rather, all four must be programmed in sequence, no padding allowed. \overline{PAE} and \overline{PAF} can show a valid status only after the full set of bits have been entered. The registers can be reprogrammed, as long as all four offsets are loaded. When \overline{LD} is LOW and \overline{SEN} is HIGH, no serial write to the registers can occur.

Once parallel offset loading has been selected, then programming PAE and PAF precedes as follows: When LD and WEN are set LOW, data on the inputs Dn are written into the LSB Empty Offset Register on the first LOW-to-HIGH transition of WCLK. Upon the second LOW-to-HIGH transition of WCLK, data at the inputs are written into the MSB Empty Offset Register. Upon the third LOW-to-HIGH transition of WCLK, data at the inputs are written into the LSB Full Offset Register. Upon the fourth LOW-to-HIGH transition of WCLK, data at the inputs are written into the MSB Full Offset Register. The fifth transition of WCLK writes, once again, to the LSB Empty Offset Register.

To ensure proper programming (serial or parallel) of the offset registers, no read operation is permitted from the time of reset (master or partial) to the time of programming. (During this period, the read pointer must be pointing to the first location of the memory array.) After the programming has been accomplished, read operations may begin.

Write operations to memory are allowed before and during the parallel programming sequence. In this case, the programming of all offset registers does not have to occur at one time. One or two offset registers can be written to and then, by bringing $\overline{\text{LD}}$ HIGH, write operations can be redirected to the FIFO memory. When $\overline{\text{LD}}$ is set LOW again, and $\overline{\text{WEN}}$ is LOW, the next offset register in sequence is written to. As an alternative to holding $\overline{\text{WEN}}$ LOW and toggling $\overline{\text{LD}}$, parallel programming can also be interrupted by setting $\overline{\text{LD}}$ LOW and toggling $\overline{\text{WEN}}$.

Write operations to memory are allowed before and during the serial programming sequence. In this case, the programming of all offset bits does not have to occur at once. A select number of bits can be written to the SI input and then, by bringing \overline{LD} and \overline{SEN} HIGH, data can be written to FIFO memory via D_D by toggling \overline{WEN} . When \overline{WEN} is brought HIGH with \overline{LD} and \overline{SEN} restored to a LOW, the next offset bit in sequence is written to the registers via SI. If a mere interruption of serial programming is desired, it is sufficient either to set \overline{LD} LOW and deactivate \overline{SEN} or to set \overline{SEN} LOW and deactivate \overline{LD} . Once \overline{LD} and \overline{SEN} are both restored to a LOW level, serial offset programming continues from where it left off.

Note that the status of a partial flag (PAE or PAF) output is invalid during the programming process. From the time parallel programming has begun, a partial flag output will not be valid until the appropriate offset words have been written to the LSB and MSB registers pertaining to that flag. From the time serial programming

has begun, neither partial flag will be valid until the full set of bits required to fill all the offset registers has been written. Measuring from the rising WCLK edge that achieves either of the above criteria; \overline{PAF} will be valid after two more rising WCLK edges plus tPAF, \overline{PAE} will be valid after the next two rising RCLK edges plus tPAE (Add one more RCLK cycle if tSKEW2 is not met.)

The act of reading the offset registers employs a dedicated read offset register pointer. The contents of the offset registers can be read on the output lines when \overline{LD} is set LOW and \overline{REN} is set LOW; then, data are read via Q_n from the LSB Empty Offset Register on the first LOW-to-HIGH transition of RCLK. Upon the second LOW-to-HIGH transition of RCLK, data are read from the MSB Empty Offset Register. Upon the third LOW-to-HIGH transition of RCLK, data are read from the LSB Full Offset Register. Upon the fourth LOW-to-HIGH transition of RCLK, data are read from the MSB Full Offset Register. The fifth transition of RCLK reads, once again, from the LSB Empty Offset Register.

It is permissible to interrupt the offset register access sequence with reads or writes to memory. The interruption is accomplished by deasserting \overline{REN} , \overline{LD} , or both together. When \overline{REN} and \overline{LD} are restored to a LOW level, access of the registers continues where it left off.

 $\overline{\text{LD}}$ functions the same way in both IDT Standard and FWFT modes.

FREQUENCY SELECT INPUT (FS)

An internal state machine manages the movement of data through the SuperSync FIFO. The FS line determines whether RCLK or WCLK will synchronize the state machine. Tie FS to Vcc if the RCLK line is running at a lower frequency than the WCLK line. In this case, the state machine will be synchronized to WCLK. Tie FS to GND if the RCLK line is running at a higher frequency than the WCLK line. In this case, the state machine will be synchronized to RCLK. Note that FS must be set so the clock line running at the higher frequency drives the state machine; this ensures efficient handling of the data within the FIFO. If the same clock signal drives both the WCLK and the RCLK pins, then tie FS to GND.

The frequency of the clock tied to the state machine (referred to as the "selected clock") may be changed at any time, so long as it is always greater than or equal to the frequency of the clock that is not tied to the state machine (referred to as the "non-selected clock"). The frequency of the non-selected clock can also be varied with time, so long as it never exceeds the frequency of the selected clock. To be more specific, the frequencies of both RCLK and WCLK may be varied during FIFO operation, provided that, at any given point in time, the cycle period of the selected clock is equal to or less than the cycle period of the non-selected clock.

The selected clock must be continuous. It is, however, permissible to stop the non-selected clock. Note, so long as RCLK is idle, EF/OR and PAE will not be updated. Likewise, as long as WCLK is idle, FF/IR and PAF will not be updated.

Changing the FS setting during FIFO operation (i.e. reading or writing) is not permitted; however, such a change at the time of Master Reset or Partial Reset is all right. FS is an asynchronous input.

OUTPUTS:

FULL FLAG (FF/IR)

This is a dual purpose pin. In IDT Standard mode, the Full Flag (\overline{FF}) function is selected. When the FIFO is full (i.e. the write pointer catches up to the read pointer), \overline{FF} will go LOW, inhibiting further write operation. When \overline{FF} is HIGH, the FIFO is not full. If no reads are performed after a reset (either \overline{MRS} or \overline{PRS}), \overline{FF} will go LOW after 16,384 writes to the IDT72261 and 32,768 writes to the IDT72271.

In FWFT mode, the Input Ready ($\overline{\text{IR}}$) function is selected. $\overline{\text{IR}}$ goes LOW when memory space is available for writing in data. When there is no longer any free space left, $\overline{\text{IR}}$ goes HIGH, inhibiting further write operation. If no reads are performed after a reset (either $\overline{\text{MRS}}$ or $\overline{\text{PRS}}$), $\overline{\text{IR}}$ will go HIGH after 16,385 writes for the IDT72261 and 32,769 writes for the IDT72271.

The \overline{IR} status not only measures the contents of the FIFO memory, but also counts the presence of a word in the output register. Thus, in FWFT mode, the total number of writes necessary to deassert \overline{IR} is one greater than needed to assert \overline{FF} in IDT Standard mode.

FF/IR is synchronized to WCLK. It is double-registered to enhance metastable immunity.

EMPTY FLAG (EF/OR)

This is a dual purpose pin. In the IDT Standard mode, the Empty Flag ($\overline{\text{EF}}$) function is selected. When the FIFO is empty (i.e. the read pointer catches up to the write pointer), $\overline{\text{EF}}$ will go LOW, inhibiting further read operations. When $\overline{\text{EF}}$ is HIGH, the FIFO is not empty.

When writing the first word to an empty FIFO, the deassertion time of $\overline{\text{EF}}$ is variable, and can be represent by the First Word Latency parameter, tFWL1, which is measured from the rising WCLK edge that writes the first word to the rising RCLK edge that updates the flag. tFWL1 includes any delays due to clock skew and can be expressed as follows:

where Tf is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the RCLK period. Since no read can take place until $\overline{\text{EF}}$ goes HIGH, the tFwL1 delay determines how early the first word can be available at Qn. This delay has no effect on the reading of subsequent words.

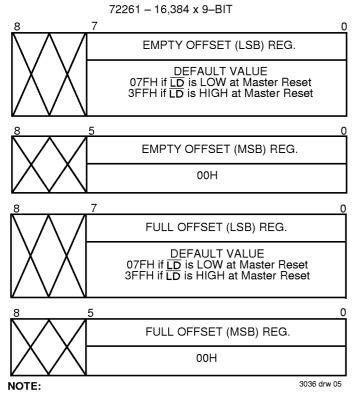
In FWFT mode, the Output Ready (\overline{OR}) function is selected. \overline{OR} goes LOW at the same time that the first word written to an empty FIFO appears valid on the outputs. \overline{OR} goes HIGH one cycle after RCLK shifts the last word from the FIFO memory to the outputs. Then further data reads are inhibited until \overline{OR} goes LOW again.

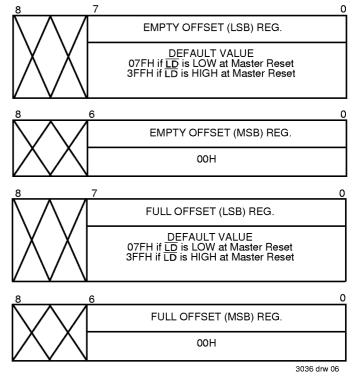
When writing the first word to an empty FIFO, the assertion time of \overline{OR} is variable, and can be represented by the First Word Latency parameter, tFWL2, which is measured from the rising WCLK edge that writes the first word to the rising RCLK edge that updates the flag. tFWL2 includes any delay due to clock skew and can be expressed as follows:

$$tFWL2 max. = 10*Tf + 3*TRCLK (in ns)$$

where Tf is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the RCLK period. Note that the First Word Latency in FWFT mode is one RCLK cycle longer than in IDT Standard mode. The tFWL2 delay determines how early

72271 - 32,768 x 9-BIT





1. Any bits of the offset register not being programmed should be set to zero.

Figure 3. Offset Register Location and Default Values

the first word can be available at Qn. This delay has no effect on the reading of subsequent words.

EF/OR is synchronized to the RCLK. It is double-registered to enhance metastable immunity.

PROGRAMMABLE ALMOST-FULL FLAG (PAF)

The Programmable Almost-Full flag (PAF) will go LOW when the FIFO reaches the almost-full condition as specified by the offset m stored in the Full Offset register.

At the time of Master Reset, depending on the state of \overline{LD} , one of two possible default offset values are chosen. If \overline{LD} is LOW, then m = 07FH and the \overline{PAF} switching threshold is 127 words from the full boundary, if \overline{LD} is HIGH, then m = 3FFH and the \overline{PAF} switching threshold is 1,023 words away from the full boundary.

Any integral value of m from 0 to the maximum FIFO depth minus 1 (16,383 words for the IDT72261, 32,767 words for the IDT72271) can be programmed into the Full Offset register.

In IDT Standard mode, if no reads are performed after reset (MRS or PRS), PAF will go LOW after (16,384-m) writes to the IDT72261, and (32,768-m) writes to the IDT72271.

In FWFT mode, if no reads are performed after reset (\overline{MRS} or \overline{PRS}), \overline{PAF} will go LOW after (16,385-m) writes to the

IDT72261, and (32,769-m) writes to the ID72271. In this case, the first word written to an empty FIFO does not stay in memory, but goes unrequested to the output register; therefore, it has no effect on determining the state of PAF.

Note that even though PAF is programmed to switch LOW during the first word latency period (tFWL), attempts to read data will be ignored until EF goes HIGH indicating that data is available at the output port. This is true for both timing modes.

PAF is synchronous and updated on the rising edge of WCLK. It is double-registered to enhance metastable immunity.

PROGRAMMABLE ALMOST-EMPTY FLAG (PAE)

The Programmable Almost-Empty flag (PAE) will go LOW when the FIFO reaches the almost-empty condition as specified by the offset n stored in the Empty Offset register.

At the time of Master Reset, depending on the state of \overline{LD} , one of two possible default offset values are chosen. If \overline{LD} is LOW, then n = 07FH and the \overline{PAE} switching threshold is 127 words from the empty boundary, if \overline{LD} is HIGH, then n = 3FFH and the \overline{PAE} switching threshold is 1,023 words away from the empty boundary.

TABLE I — STATUS FLAGS FOR IDT STANDARD MODE

Number of Words in	FIFO Memory (1)					
72261	72271	FF	PAF	HF	PAE	EF
0	0	Н	Н	Н	L	L
1 to n ⁽²⁾	1 to n ⁽²⁾	Н	Н	Н	L	Η
(n+1) to 8,192	(n+1) to16,384	Н	Н	Н	Н	Н
8,193 to (16,384-(m+1))	16,385 to (32,768-(m+1))	Н	Н	L	Н	Н
(16,384-m) ⁽³⁾ to 16,383	(32,768-m) ⁽³⁾ to 32,767	Н	L	L	Н	Н
16,384	32,768	L	L	L	Н	Н

NOTES:

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- 1. Data in the output register does not count as a "word in FIFO memory". Since, in FWFT mode, the first word written to an empty FIFO goes unrequested to the output register (no read operation necessary), it is not included in the FIFO memory count.
- 2. n = Empty Offset, Default Values: n = 127 when parallel offset loading is selected or n=1,023 when serial offset loading is selected.
- 3. m = Full Offset, Default Values: m = 127 when parallel offset loading is selected or m =1,023 when serial offset loading is selected.

TABLE II — STATUS FLAGS FOR FWFT MODE

Number of Words in	FIFO Memory (1)					
72261	ĪR	PAF	HF	PAE	OR	
0	0	L	Н	Н	L	H ⁽⁴⁾
1 to n ⁽²⁾	1 to n ⁽²⁾	L	Н	Н	L	L
(n+1) to 8,192	(n+1) to16,384	L	Н	Н	Н	L
8,193 to (16,384-(m+1))	16,385 to (32,768-(m+1))	L	Н	L	Н	L
(16,384-m)(3) to 16,383	(32,768-m)(3) to 32,767	L	L	L	Н	L
16,384	32,768	Н	Ĺ	Ĺ	Н	L

NOTES:

- 1. Data in the output register does not count as a "word in FIFO memory". Since, in FWFT mode, the first word written to an empty FIFO goes unrequested to the output register (no read operation necessary), it is not included in the FIFO memory count.
- 2. n = Empty Offset, Default Values: n = 127 when parallel offset loading is selected or n=1,023 when serial offset loading is selected.
- 3. m = Full Offset, Default Values: m = 127 when parallel offset loading is selected or m =1,023 when serial offset loading is selected.
- 4. Following a reset (Master or Partial), the FIFO memory is empty and OR = HIGH. After writing the first word, the FIFO memory remains empty, the data is placed into the output register, and OR goes LOW. In this case, or any time the last word in the FIFO memory has been read into the output register; a rising RCLK edge, enabled by REN, will set OR HIGH.

Any integral value of n from 0 to the maximum FIFO depth minus 1 (16,383 words for the IDT72261, 32,767 words for the IDT72271) can be programmed into the Empty Offset register.

In IDT Standard mode, if no reads are performed after reset (MRS or PRS), PAE will go HIGH after (n+1) writes to the IDT72261/72271.

In FWFT mode, if no reads are performed after reset (MRS or PRS), PAE will go HIGH after (n+2) writes to the IDT72261/72271. In this case, the first word written to an empty FIFO does not stay in memory, but goes unrequested to the output register; therefore, it has no effect on determining the state of PAE.

Note that even though PAE is programmed to switch HIGH during the first word latency period (tFWL), attempts to read data will be ignored until EF goes HIGH indicating that data is available at the output port. This is true for both timing modes.

PAE is synchronous and updated on the rising edge of RCLK. It is double-registered to enhance metastable immunity.

HALF-FULL FLAG (HF)

This output indicates a half-full memory. The rising WCLK edge that fills the memory beyond half-full sets $\overline{\text{HF}}$ LOW. The

flag remains LOW until the difference between the write and read pointers becomes less than or equal to one half of the total depth of the device, the rising RCLK edge that accomplishes this condition also sets $\overline{\text{HF}}$ HIGH.

In IDT Standard mode, if no reads are performed after reset ($\overline{\text{MRS}}$ or $\overline{\text{PRS}}$), $\overline{\text{HF}}$ will go LOW after (D/2+1) writes, where D is the maximum FIFO depth (16,384 words for the IDT72261, 32,768 words for the IDT72271).

In FWFT mode, if no reads are performed after reset ($\overline{\text{MRS}}$ or $\overline{\text{PRS}}$), $\overline{\text{HF}}$ will go LOW after (D/2+2) writes to the IDT72261/72271. In this case, the first word written to an empty FIFO does not stay in memory, but goes unrequested to the output register; therefore, it has no effect on determining the state of $\overline{\text{HF}}$

Because HF uses both RCLK and WCLK for synchronization purposes, it is asynchronous.

DATA OUTPUTS (Qo-Q8)

Qo-Q8 are data outputs for 9-bit wide data.

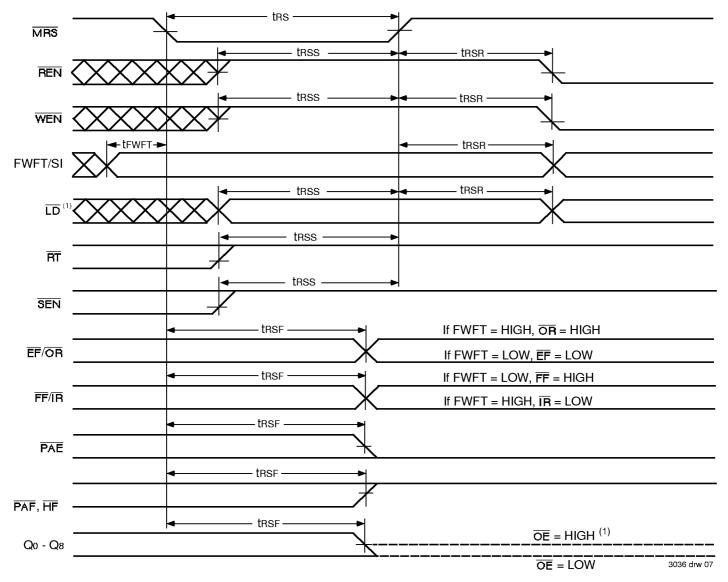


Figure 4. Master Reset Timing

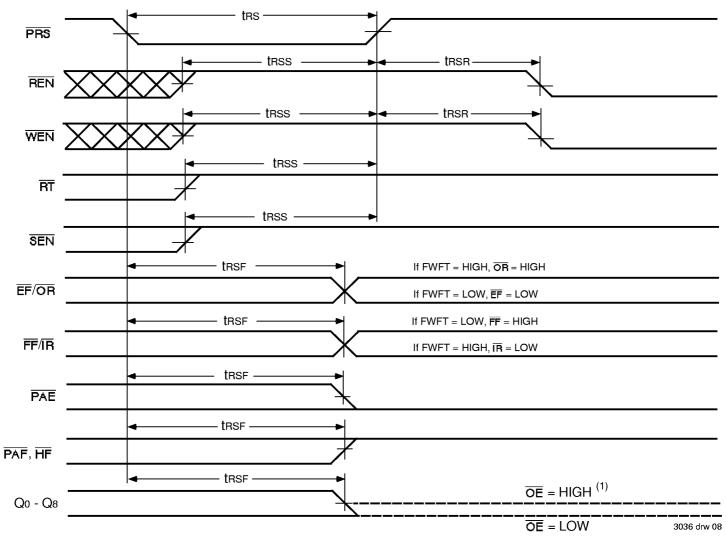
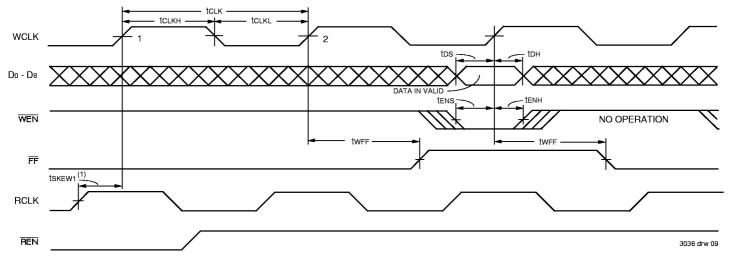
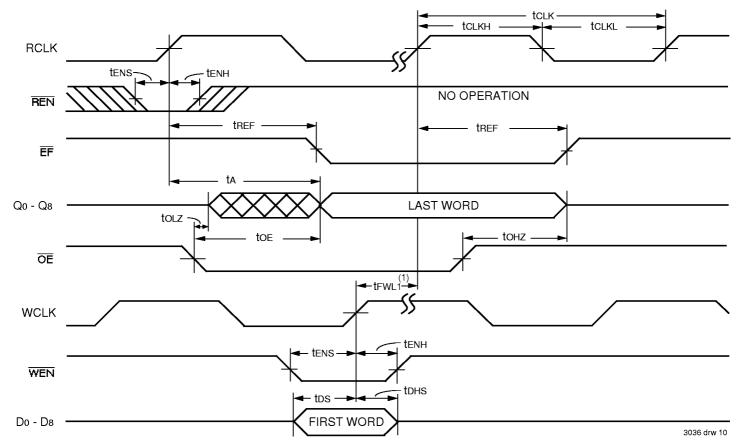


Figure 5. Partial Reset Timing



- 1. tskew1 is the minimum time between a rising RCLK edge and a rising WCLK edge to guarantee that FF will go HIGH (after one WCLK cycle plus twrF). If the time between the rising edge of RCLK and the rising edge of WCLK is less than tskew1, then the FF deassertion may be delayed an extra WCLK cycle. 2. LD = HIGH

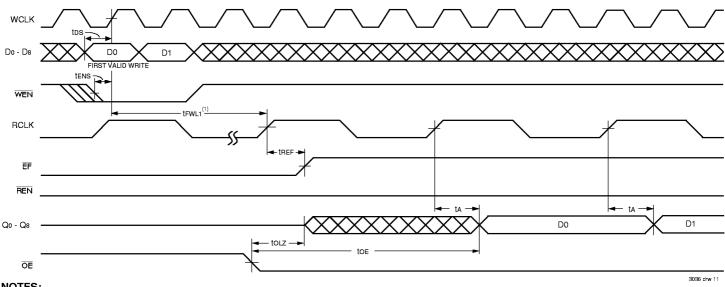
Figure 6. Write Cycle Timing (IDT Standard Mode)



- tFWL1 contributes a variable delay to the overall first word latency (this parameter includes delays due to skew):
 tFWL1 max. (in ns) = 10*Tf + 2* TRCLK
- where Tf is either the RCLK or the WCLK period, whichever is shorter, and TROLK is the RCLK period

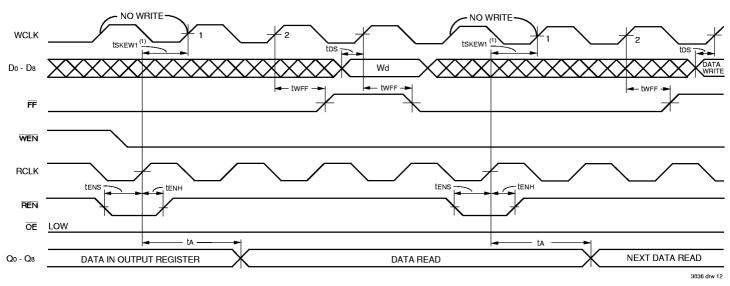
2. \overline{LD} = HIGH

Figure 7. Read Cycle Timing (IDT Standard Mode)



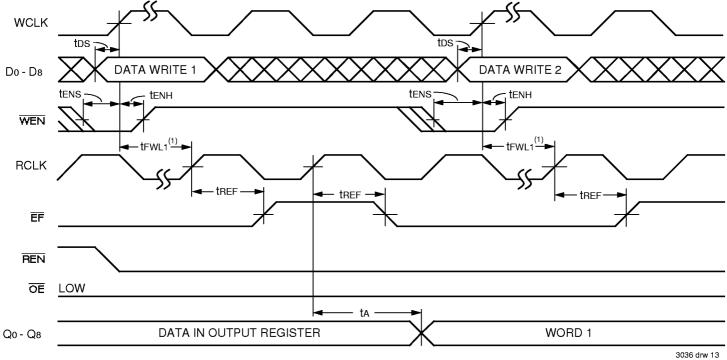
- 1. tFWL1 max. (in ns) = 10* Tf + 2* TRCLK
- Where Tr is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the RCLK period
- 2. $\overline{LD} = HIGH$

Figure 8. First Data Word Latency (IDT Standard Mode)



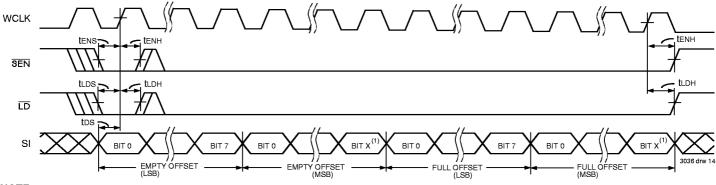
- 1. tskewi is the minimum time between a rising RCLK edge and a rising WCLK edge to guarantee that FF will go high (after one WCLK cycle pus twFF). If the time between the rising edge of the RCLK and the rising edge of the WCLK is less than tskewi, then the FF deassertion may be delayed an extra WCLK cycle.
- 2. \overline{LD} = HIGH

Figure 9. Full Flag Timing (IDT Standard Mode)



- tFWL1 max. (in ns) = 10*Tf + 2*TRCLK
 Where Tf is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the period.
- 2. LD = HIGH

Figure 10. Empty Flag Timing (IDT Standard Mode)



1. For the IDT72261, X = 5. For the IDT72271, X = 6.

Figure 11. Serial Loading of Programmable Flag Registers (IDT Standard and FWFT modes)

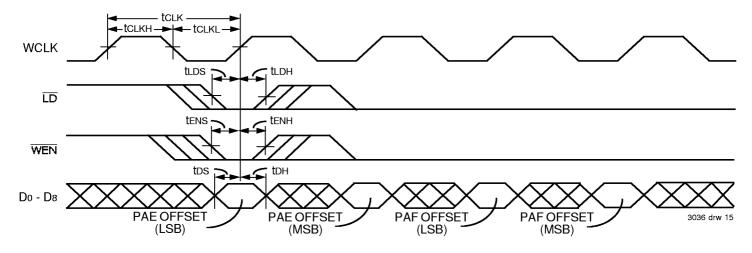
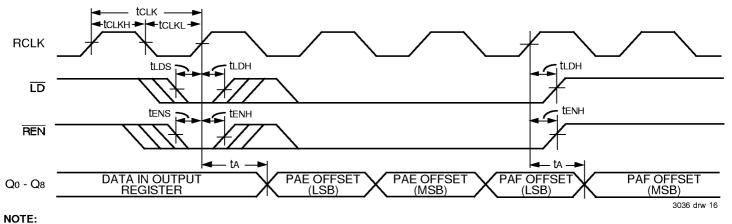
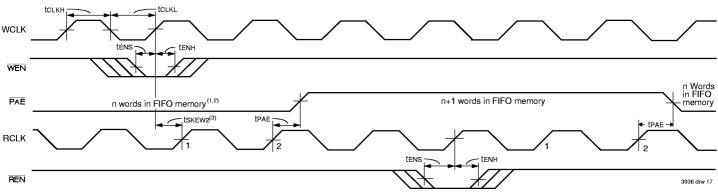


Figure 12. Parallel Loading of Programmable Flag Registers (IDT Standard and FWFT modes)



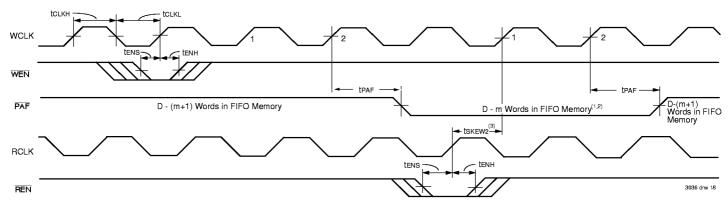
1. OE = LOW

Figure 13. Parallel Read of Programmable Flag Registers (IDT Standard and FWFT modes)



- 1. $n = \overline{PAE}$ offset
- 2. Data in the output register does not count as a "word in FIFO memory". Since, in FWFT mode, the first word written to an empty FIFO goes unrequested to the output register (no read operation necessary), it is not included in the FIFO memory count.
- 3. tskews is the minimum time between a rising WCLK edge and a rising RCLK edge for PAE to go HIGH (after one RCLK cycle plus tPAE). If the time between the rising edge of WCLK and the rising edge of RCLK is less than tskews, then the PAE deassertion may be delayed one extra RCLK cycle.

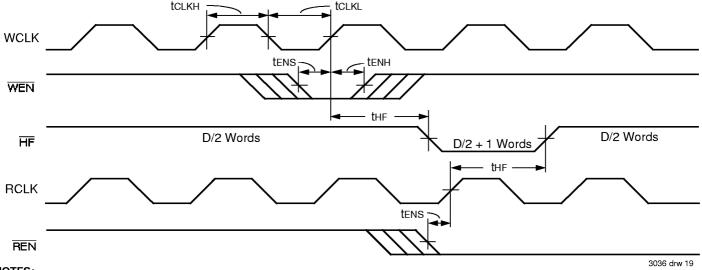
Figure 14. Programmable Almost-Empty Flag Timing (IDT Standard and FWFT modes)



NOTES

- 1. $m = \overline{PAF}$ offset, D = 16,384 for IDT72261, 32,768 words for IDT72271.
- 2. Data in the output register does not count as a "word in FIFO memory". Since, in FWFT mode, the first word written to an empty FIFO goes unrequested to the output register (no read operation necessary), it is not included in the FIFO memory count.
- 3. tskews is the minimum time between a rising RCLK edge and a rising WCLK edge for PAF to go HIGH (after one WCLK cycle plus tPAF). If the time between the rising edge of RCLK and the rising edge of WCLK is less than tskews, then the PAF deassertion time may be delayed an extra WCLK cycle.

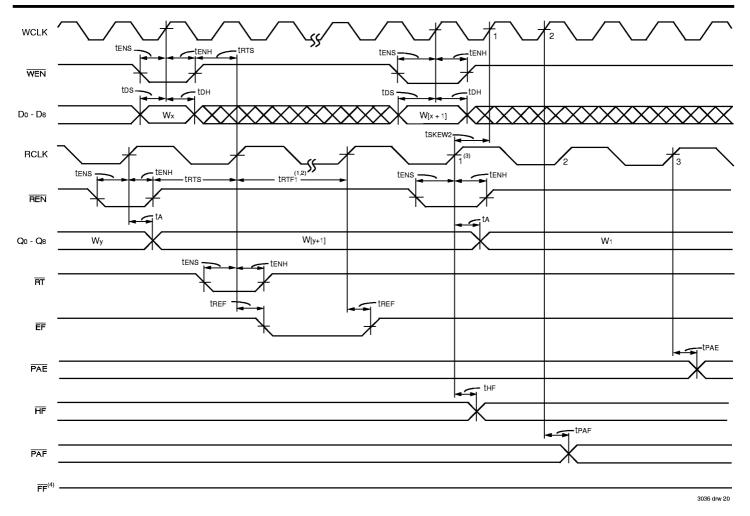
Figure 15. Programmable Almost-Full Flag Timing (IDT Standard and FWFT modes)



NOTES

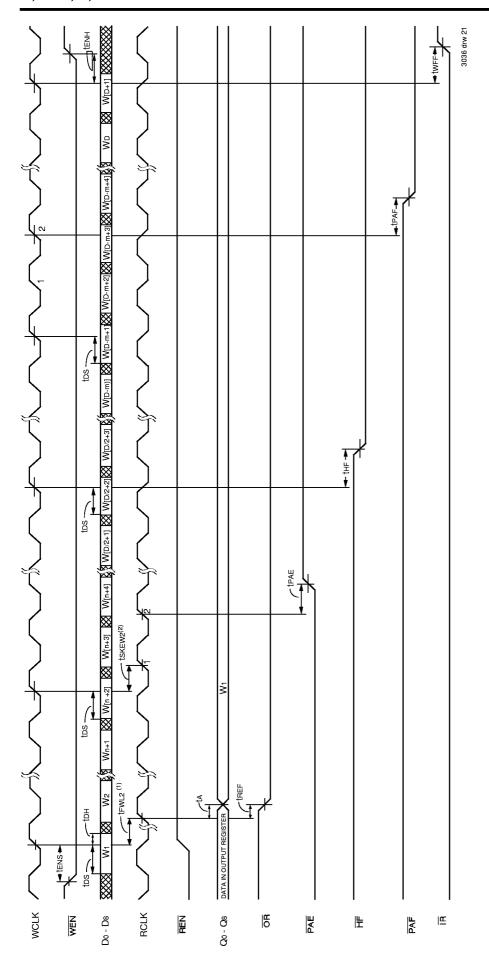
1. D = maximum FIFO depth = 16,384 for IDT72261, 32,768 words for IDT72271.

Figure 16. Half-Full Flag Timing (IDT Standard and FWFT modes)



- 1. trtf1 contributes a variable delay to the overall retransmit recovery time: treft1 max = 14*Tf + 3*Trclk (in ns)
 - Where Tf is either the RCLK or the WCLK period, whichever is shorter, and TRCLK is the RCLK period.
- 2. Retransmit Setup is complete after EF returns HIGH, only then can a read operation begin. Write operations are permitted after one of two conditions have been met: EF is HIGH or 14 cycles of the faster clock (RCLK or WCLK) have elapsed since the RCLK rising edge enabled by the RT pulse.
- 3. Following Retransmit Setup, the rising edge of RCLK that accesses the first memory location also initiates the updating of HF, PAE, and PAF.
- 4. No more than D 2 words (D = 16,384 words for the IDT72261, 32,768 words for the IDT72271) should have been written to the FIFO between Reset (Master or Partial) and Retransmit Setup. Therefore, FF will be HIGH throughout the Retransmit Setup procedure.
- 5. $\overleftarrow{\sf OE}$ = LOW

Figure 17. Retransmit Timing (IDT Standard mode)



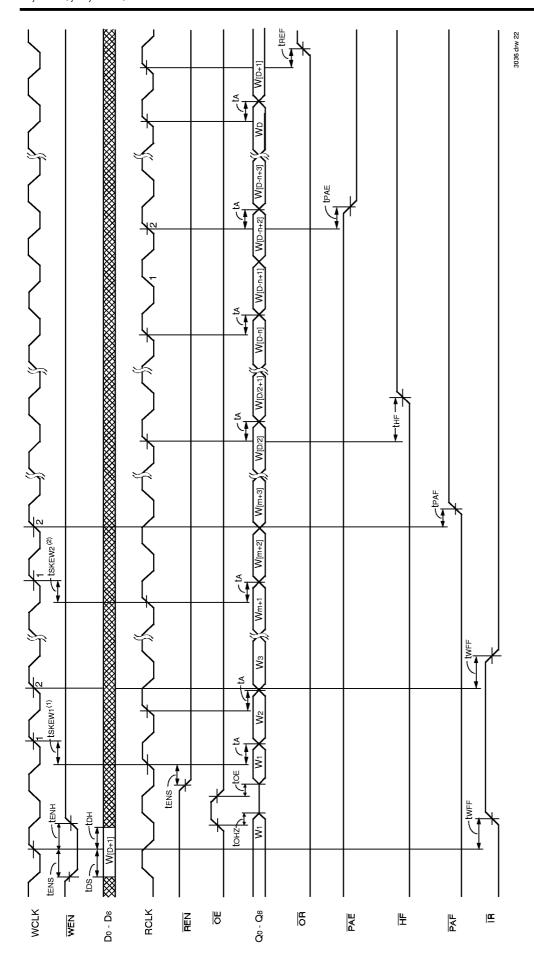
1. tFWL2 max. (in ns) = $10^*Tf + 3^*TRCLK$

where Tf is either the RCLK or the WCLK period, whichever is shorter, and Trolk is the RCLK period. tskewz is the minimum time between a rising WCLK edge and a rising RCLK edge for PAE to go HIGH (after one RCLK cycle plus that). If the time between the rising edge of WCLK and the rising edge of WCLK and the rising edge of ACLK is less than tskewz, then the PAE deassertion may be delayed one extra RCLK cycle. αį

დ. 4_.

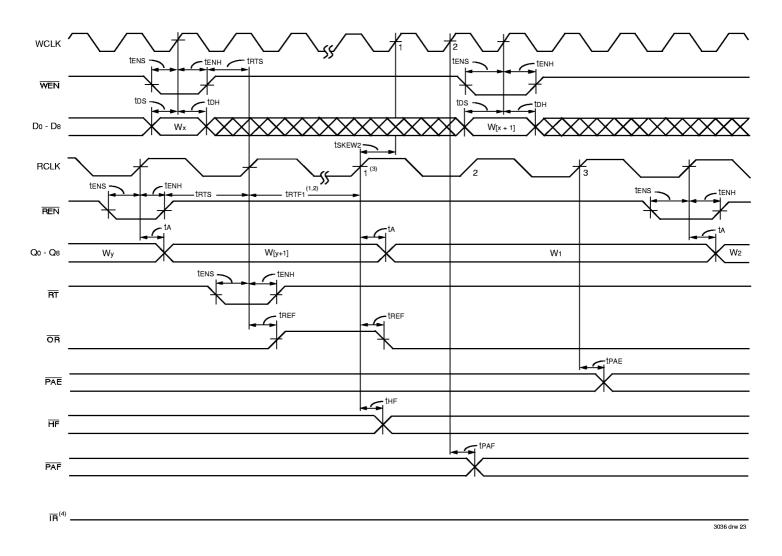
LD = HIĞH, OE = LOW n = PAF offset, D = maximum FIFO depth = 16,384 words for the IDT72261, 32,768 words for the IDT72271

Figure 18. Write Timing (First Word Fall Through Mode)



tskewr is the minimum time between a rising RCLK edge and a rising WCLK edge to guarantee that IR will go LOW (after one WCLK cycle plus twFF). If the time between the rising edge of RCLK and the rising edge of WCLK is less than tskewr, then the IR assertion may be delayed an extra WCLK cycle.
 tskewz is the minimum time between a rising RCLK edge and a rising WCLK edge for PAF to go HIGH (after one WCLK cycle plus tPAF). If the time between the rising edge of RCLK and the rising edge of WCLK is less than tskewz, then the PAF deassertion may be delayed an extra WCLK cycle.
 LD = HIGH
 n = PAF offset, D = maximum FIFO depth = 16,384 words for the IDT72261, 32,768 words for the IDT72271

Figure 19. Read Timing (First Word Fall Through Mode)



- 1. trtf2 contribute a variable delay to the overall retransmit time: trtf2 max = 14*Tf + 4*Trclk (in ns)
 - Where Tr is either the RCLK or the WCLK period, whichever is shorter, and TROLK is the RCLK period.
- 2. Retransmit Setup is complete after \overline{OR} returns LOW, only then can a read operation begin. Write operations are permitted after one of two conditions have been met: \overline{OR} is LOW or 14 cycles of the faster clock (RCLK or WCLK) have elapsed since the RCLK rising edge enabled by the \overline{RT} pulse.
- 3. Following Retransmit Setup, the rising edge of RCLK that accesses the first memory location also initiates the updating of HF, PAE and PAF.
- 4. No more than D 2 words (D = 16,384 words for the IDT72261, 32,768 words for the IDT72271) should have been written to the FIFO between Reset (Master or Partial) and Retransmit Setup. Therefore, IR will be LOW throughout the Retransmit Setup procedure.
- 5. OE = LOW

Figure 20. Retransmit Timing (FWFT mode)

OPERATING CONFIGURATIONS

SINGLE DEVICE CONFIGURATION

A single IDT72261/722171 may be used when the application requirements are for 16,384/32,768 words or less.

The IDT72261/72271 can always be used in Single Device Configuration, whether IDT Standard mode or FWFT mode has been selected. No special set up procedure is necessary.

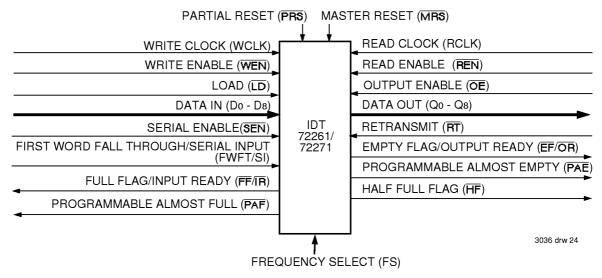
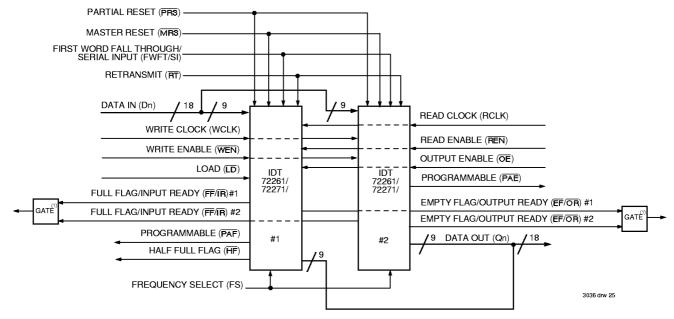


Figure 21. Block Diagram of Single 16,384 x 9 and 32,768 x 9 Synchronous FIFO

WIDTH EXPANSION CONFIGURATION

Word width may be increased simply by connecting together the control signals of multiple devices. Status flags can be detected from any one device. The exceptions are the $\overline{\text{EF}}$ and $\overline{\text{FF}}$ functions in IDT Standard mode and the $\overline{\text{IR}}$ and $\overline{\text{OR}}$ functions in FWFT mode. Because of variations in skew between RCLK and WCLK, it is possible for $\overline{\text{EF}}/\overline{\text{FF}}$ deassertion and $\overline{\text{IR}}/\overline{\text{OR}}$ assertion to vary by one cycle between FIFOs. In

IDT Standard mode, such problems can be avoided by creating composite flags, that is, ANDing EF of every FIFO, and separately ANDing FF of every FIFO. In FWFT mode, composite flags can be created by ORing OR of every FIFO, and separately ORing IR of every FIFO. Figure 22 demonstrates an 18-word width by using two IDT72261/72271s. Any word width can be attained by adding additional IDT72261/72271s.



- 1. Use an AND gate in IDT Standard mode, an OR gate in FWFT mode.
- 2. Do not connect any output control signals directly together.

Figure 22. Block Diagram of 16,384 x 18 and 32,768 x 18 Width Expansion

DEPTH EXPANSION CONFIGURATION

The IDT72261/72271 can easily be adapted to applications requiring more than 16,384/32,768 words of buffering. In FWFT mode, the FIFOs can be arranged in series (the data outputs of one FIFO connected to the data inputs of the next)—no external logic necessary. The resulting configuration provides a total depth equivalent to the sum of the depths associated with each single FIFO. Figure 23 shows a depth expansion using two IDT72261/72271s.

Care should be taken to select FWFT mode during Master Reset for all FIFOs in the depth expansion configuration. The first word written to an empty configuration will pass from one FIFO to the next ("ripple down") until it finally appears at the outputs of the last FIFO in the chain–no read operation is necessary. Each time the data word appears at the outputs of one FIFO, that device's \overline{OR} line goes LOW, enabling a write to the next FIFO in line.

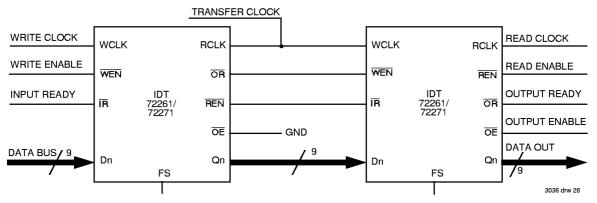


Figure 23. Block Diagram of 32,768 x 9 and 65,536 x 9 Synchronous FIFO Memory With Programmable Flags used in Depth Expansion Configuration

The \overline{OR} assertion time is variable and is described with the help of the tFWL2 parameter, which includes including delay caused by clock skew:

where TRCLK is the RCLK period and Tf is either the RCLK or the WCLK period, whichever is shorter.

The maximum amount of time it takes for a word to pass from the inputs of the first FIFO to the outputs of the last FIFO in the chain is the sum of the delays for each individual FIFO:

$$t_{FWL2(1)} + t_{FWL2(2)} + ... + t_{FWL2(N)} + N^*T_{RCLK}$$

where N is the number of FIFOs in the expansion.

Note that the additional RCLK term accounts for the time it takes to pass data between FIFOs.

The ripple down delay is only noticeable for the first word written to an empty depth expansion configuration. There will be no delay evident for subsequent words written to the configuration.

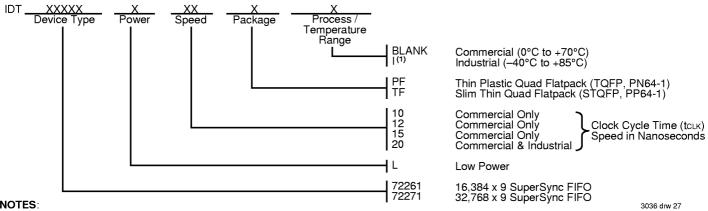
The first free location created by reading from a full depth expansion configuration will "bubble up" from the last FIFO to the previous one until it finally moves into the first FIFO of the chain. Each time a free location is created in one FIFO of the chain, that FIFO's $\overline{\text{IR}}$ line goes LOW, enabling the preceding FIFO to write a word to fill it.

The amount of time it takes for \overline{IR} of the first FIFO in the chain to assert after a word is read from the last FIFO is the sum of the delays for each individual FIFO:

where N is the number of FIFOs in the expansion and TWCLK is the WCLK period. Note that one of the three WCLK cycle accounts for Tskew1 delays.

In a SuperSync depth expansion, set FS individually for each FIFO in the chain. The Transfer Clock line should be tied to either WCLK or RCLK, whichever is faster. Both these actions result in moving, as quickly as possible, data to the end of the chain and free locations to the beginning of the chain.

ORDERING INFORMATION



1. Industrial temperature range is available by special order for speed grades faster than 20ns



CMOS SUPERSYNC FIFO™ 16,384 x 9, 32,768 x 9

IDT72261 IDT72271

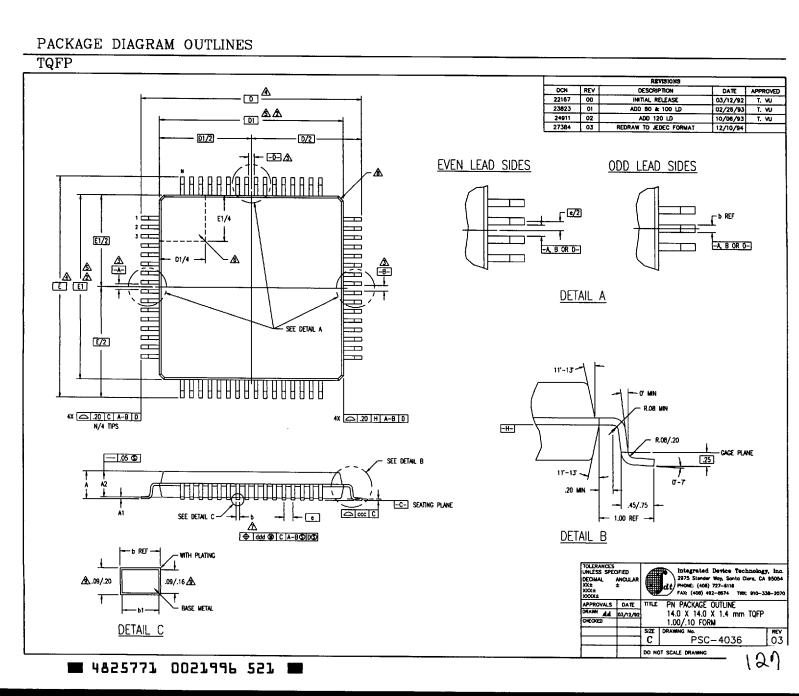
ADDENDUM

DIFFERENCES BETWEEN THE IDT72261LA/72271LA AND IDT72261L/72271L

IDT has improved the performance of the IDT72261/72271 SuperSync™ FIFOs. The new versions are designated by the "LA" mark. The LA part is pin-for-pin compatible with the original "L" version. Some differences exist between the two versions. The following table details these differences.

lte m	NEW PART	OLD PART	Comments
	72261LA 72271LA	72261L 72271L	
Pin #3	DC (Don't Care) - There is no restriction on WCLK and RCLK. See note 1.	FS (Frequency Select)	In the LA part this pin must be tied to either Vcc or GND and must not toggle after reset.
First Word Latency (IDT Standard Mode)	60ns ² + tREF + 1 TRCLK ⁴	tFWL1=10*Tf ³ + 2TRCLK ⁴ (ns)	First word latency in the LA part is a fixed value, independent of the frequency of RCLK or WCLK.
First Word Latency (FWFT Mode)	60ns ² + tREF + 2 TRCLK ⁴	tFWL2=10*Tf ³ + 3TRCLK ⁴ (ns)	First word latency in the LA part is a fixed value, independent of the frequency of RCLK or WCLK
Retransmit Latency (IDT Standard Mode)	60ns ² + tREF + 1 TRCLK ⁴	trtf1=14*Tf ³ + 3Trclk ⁴ (ns)	Retransmit latency in the LA part is a fixed value, independent of the frequency of RCLK or WCLK
Retransmit Latency (FWFT Mode)	60ns² + tREF + 2 TRCLK⁴	trtf2=14*Tf ³ + 4TrclK ⁴ (ns)	Retransmit latency in the LA part is a fixed value, independent of the frequency of RCLK or WCLK
lcc1	75mA	150mA	Active supply current
ICC2	20mA	15mA	Standby current
Typical lcc1 ⁵	15 + 1.85*fs + 0.02*CL*fs (mA)	Not Given	Typical lcc1 Current calculation.

- 1. WCLK and RCLK can vary independently and can be stopped. There is no restriction on operating WCLK and RCLK.
- 2. This is tSKEW3.
- 3. Tf is the period of the 'selected clock'.
- 4. Trclk is the cycle period of the read clock.
- 5. Typical Icc1 is based on Vcc = 5V, tA =25°C, fs= WCLK frequency = RCLK frequency (in MHz using TTL levels), data switching at fs/2, CL = Capacitive Load (in pF).



PACKAGE DIAGRAM OUTLINES

TQFP (Continued)

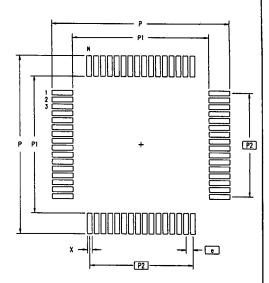
	DWG #		PN64-	1	DWC	G #	PN80	-1	DW	G /	PN10	0-1	DW	3 #	PN12	0-1
Ş	JEDE	C VARIAT	ION	Z	JEDE	ION	N	JEDEC VARIATION			N	JEDEC VARIA		RIATION		
B	BP			P		BQ] P		BR		1 9 1		BS		P
,	MIN	NOM	MAX	E	MIN	NOM	MAX	É	MIN	NOM	MAX] É	MIN	NOM	MAX	Ė
A	-		1.60		_	-	1.60		-	- ⁻	1.60			-	1.60	
A1	.05	.10	.15		.05	.10	.15		.05	.10	.15	П	.05	.10	.15	
A2	1.35	1.40	1.45		1.35	1.40	1.45		1.35	1.40	1.45		1.35	1.40	1.45	
٥		6.00 BS	C	4	1	16.00 BSC		4	16.00 BSC		4	16.00 BSC		4		
01	1	14.00 BS	С	5,2	1	4.00 BS	c	5,2	14.00 BSC		5,2	14.00 BSC		5,2		
E	1	16.00 BS	C	4	1	6.00 85	С	4	16.00 BSC		4	16.00 BSC		4		
E١	.1	4.00 BS	С	5,2	1	4.00 BS	С	5,2	14.00 BSC		С	5,2	14.00 BSC		5.2	
N		64				80				100		П		120		
e		.80 BSC				.65 BSC .50 BSC .40 BS		.50 BSC		.50 BSC		.40 BSC				
Ь	.30	.37	.45	7	.22	.32	.38	7	.17	.22	.27	7	.13	.18	.23	7
ы	.30	.35	.40		.22	.30	.33		.17	.20	.23		.13	.16	.19	1
ccc	-	-	.10		-	_	.10	1	-	i -	.08	\Box	_	 -	.08	
ppp	-	_	.20		-	-	.13		-	 	.08		_	-	.07	1

NOTES:

- 1 ALL DIMENSIONING AND TOLERANCING CONFORM TO ANSI Y14.5M-1982
- TOP PACKAGE MAY BE SMALLER THAN BOTTOM PACKAGE BY .15 mm
- ⚠ DATUMS A-B AND -D- TO BE DETERMINED AT DATUM PLANE -H-
- Δ DIMENSIONS D AND ε ARE TO BE DETERMINED AT SEATING PLANE -C-
- DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS .25 mm PER SIDE. D1 AND E1 ARE MAXIMUM BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH
- DETAILS OF PIN 1 IDENTIFIER IS OPTIONAL BUT MUST BE LOCATED WITHIN THE ZONE INDICATED
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION IS .08 mm in excess of the 6 dimension at maximum material condition. Dambar cannot be located on the lower radius or the foot.
- A EXACT SHAPE OF EACH CORNER IS OPTIONAL
- THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .10 AND .25 mm FROM THE LEAD TIP
- 10 ALL DIMENSIONS ARE IN MILLIMETERS
- 11 This outline conforms to jedec publication 95 registration MO-136, variation 8P, 8Q, 8R & 8S

REVISIONS					
DCN REV		DESCRIPTION	DATE	APPROVED	
22167	00	INITIAL RELEASE	03/12/92	T. VU	
23823	01	ADD 80 & 100 LD	02/26/93	T. VU	
24911	02	ADD 120 LD	10/06/93	T. VU	
27384	03	REDRAW TO JEDEC FORMAT	11/18/94		

LAND PATTERN DIMENSIONS

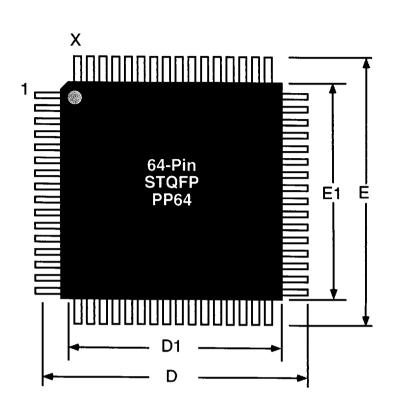


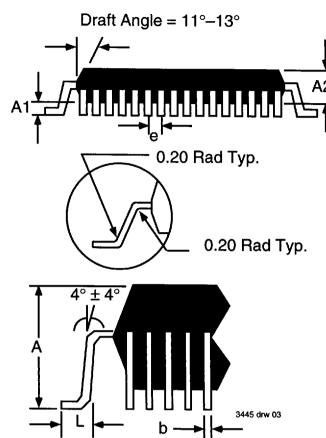
	MIN	MAX	MRN	MAX	MIN	MAX	MIN	MAX
ď	16.80	17.00	16.80	17.00	16.80	17.00	16.80	17.00
P1	13.80	14.00	13.80	14.00	13.80	14.00	13.80	14.00
P2	12.00	BSC	12.35 BSC		12.00 BSC		11.60 BSC	
Χ	.40	.60	.30	.50	.30	40	.20	.30
e	.80 BSC		.65 BSC		.50 BSC		.40 BSC	
N	64 80		100		120			

TOLERANCES UNLESS SPE DECIMAL XX± XXX± XXXX±	CIRED ANGULAR ±		Integrated Device Technology 2975 Stender Way, Santa Clore, CA 4 PHONE: (408) 727-5116 FAM: (408) 492-8874 TWM: 910-33	95054
APPROVALS	DATE	TITLE	PN PACKAGE OUTLINE	
DRAWN ALA	03/12/92		14.0 X 14.0 X 1.4 mm TQFP	
CHECKED	· · · ·		1.00/.10 FORM	
		SIZE	DRAWING No.	REV
		С	PSC-4036	03
		DO NO	OT SCALE DRAWING	<u>()</u>
			la	K

■ 4825771 0021997 468 **■**

PACKAGE DIMENSIONS





DIMENSIONS

64-PIN STQFP WITH 10MM BODY

Dimension		5	
DImension	Tolerance	Dimension	
Letter	(mm)	(mm)	
A	Max.	1.60	
A1	<u>+</u> .05	0.10	
A2	<u>+</u> .05	1.45	
D	<u>+</u> .10	12.00	
D1	<u>+</u> .10	10.00	
E	<u>+</u> .10	12.00	
E1	<u>+</u> .10	10.00	
Ĺ	<u>+</u> 15	0.60	
е	Basic	0.50	
b	.05	0.22	